

Notice of References Cited	Application/Control No. 10/063,980		Applicant(s)/Patent Under Reexamination DEWANJEE, PIJUSH K.	
	Examiner David Buttner		Art Unit 1712	Page 1 of 1

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	L	US-			
	M	US-			

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	U	chemical registry # 5285-60-9			
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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